

## 100304 Low Power Quint AND/NAND Gate

### General Description

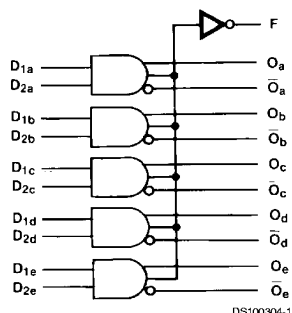
The 100304 is monolithic quint AND/NAND gate. The Function output is the wire-NOR of all five AND gate outputs. All inputs have 50 kΩ pull-down resistors.

### Features

- Low Power Operation

- 2000V ESD protection
- Pin/function compatible with 100104
- Voltage compensated operating range = -4.2V to -5.7V
- Available to industrial grade temperature range
- Available to Standard Microcircuit Drawing (SMD) 5962-9153701

### Logic Symbol



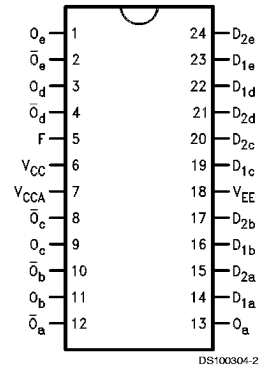
### Logic Equation

$$F = \overline{(\overline{D_{1a}} \cdot \overline{D_{2a}})} + (\overline{D_{1b}} \cdot D_{2b}) + \overline{D_{1c}} \cdot \overline{D_{2c}} + (\overline{D_{1d}} \cdot D_{2d}) + (\overline{D_{1e}} \cdot \overline{D_{2e}})$$

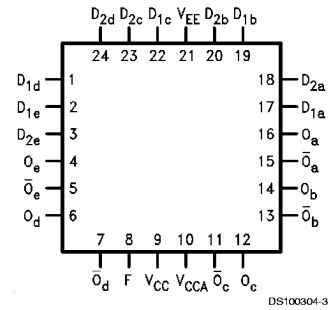
| Pin Names                       | Description                |
|---------------------------------|----------------------------|
| $D_{na}-D_{ne}$                 | Data Inputs                |
| F                               | Function Output            |
| $O_a-O_e$                       | Data Outputs               |
| $\overline{O_a}-\overline{O_e}$ | Complementary Data Outputs |

## Connection Diagrams

24-Pin DIP



24-Pin Quad Cerpak



## Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/ Distributors for availability and specifications.

Above which the useful life may be impaired

Storage Temperature ( $T_{STG}$ )  $-65^{\circ}\text{C}$  to  $+150^{\circ}\text{C}$

Maximum Junction Temperature ( $T_J$ )

Ceramic  $+175^{\circ}\text{C}$

$V_{EE}$  Pin Potential to Ground Pin  $-7.0\text{V}$  to  $+0.5\text{V}$

Input Voltage (DC)  $V_{EE}$  to  $+0.5\text{V}$

Output Current (DC Output HIGH)  $-50\text{ mA}$

ESD (Note 2)

$\geq 2000\text{V}$

## Recommended Operating Conditions

Case Temperature ( $T_C$ )

Military

$-55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$

Supply Voltage ( $V_{EE}$ )

$-5.7\text{V}$  to  $-4.2\text{V}$

**Note 1:** Absolute maximum ratings are those values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

**Note 2:** ESD testing conforms to MIL-STD-883, Method 3015.

## Military Version DC Electrical Characteristics

$V_{EE} = -4.2\text{V}$  to  $-5.7\text{V}$ ,  $V_{CC} = V_{CCA} = \text{GND}$ ,  $T_C = -55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$

| Symbol    | Parameter            | Min   | Max   | Units         | $T_C$                                           | Conditions                                                 | Notes                                                            |
|-----------|----------------------|-------|-------|---------------|-------------------------------------------------|------------------------------------------------------------|------------------------------------------------------------------|
| $V_{OH}$  | Output HIGH Voltage  | -1025 | -870  | mV            | $0^{\circ}\text{C}$ to $+125^{\circ}\text{C}$   | $V_{IN} = V_{IH} (\text{Max})$<br>or $V_{IL} (\text{Min})$ | Loading with $50\Omega$ to $-2.0\text{V}$<br><br>(Notes 3, 4, 5) |
|           |                      | -1085 | -870  | mV            | $-55^{\circ}\text{C}$                           |                                                            |                                                                  |
| $V_{OL}$  | Output LOW Voltage   | -1830 | -1620 | mV            | $0^{\circ}\text{C}$ to $+125^{\circ}\text{C}$   | $V_{IN} = V_{IH} (\text{Min})$<br>or $V_{IL} (\text{Max})$ | Loading with $50\Omega$ to $-2.0\text{V}$<br><br>(Notes 3, 4, 5) |
|           |                      | -1830 | -1555 | mV            | $-55^{\circ}\text{C}$                           |                                                            |                                                                  |
| $V_{OHC}$ | Output HIGH Voltage  | -1035 |       | mV            | $0^{\circ}\text{C}$ to $+125^{\circ}\text{C}$   | $V_{IN} = V_{IH} (\text{Min})$<br>or $V_{IL} (\text{Max})$ | Loading with $50\Omega$ to $-2.0\text{V}$<br><br>(Notes 3, 4, 5) |
|           |                      | -1085 |       | mV            | $-55^{\circ}\text{C}$                           |                                                            |                                                                  |
| $V_{OLC}$ | Output LOW Voltage   |       | -1610 | mV            | $0^{\circ}\text{C}$ to $+125^{\circ}\text{C}$   | $V_{IN} = V_{IH} (\text{Min})$<br>or $V_{IL} (\text{Max})$ | Loading with $50\Omega$ to $-2.0\text{V}$<br><br>(Notes 3, 4, 5) |
|           |                      |       | -1555 | mV            | $-55^{\circ}\text{C}$                           |                                                            |                                                                  |
| $V_{IH}$  | Input HIGH Voltage   | -1165 | -870  | mV            | $-55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$ | Guaranteed HIGH Signal for All Inputs                      | (Notes 3, 4, 5, 6)                                               |
| $V_{IL}$  | Input LOW Voltage    | -1830 | -1475 | mV            | $-55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$ | Guaranteed LOW Signal for All Inputs                       | (Notes 3, 4, 5, 6)                                               |
| $I_{IL}$  | Input LOW Current    | 0.50  |       | $\mu\text{A}$ | $-55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$ | $V_{EE} = -4.2\text{V}$<br>$V_{IN} = V_{IL} (\text{Min})$  | (Notes 3, 4, 5)                                                  |
| $I_{IH}$  | Input High Current   |       |       |               |                                                 | $V_{EE} = -5.7\text{V}$<br>$V_{IN} = V_{IH} (\text{Max})$  | (Notes 3, 4, 5)                                                  |
|           | $D_{2a}-D_{2e}$      |       | 250   | $\mu\text{A}$ | $0^{\circ}\text{C}$ to $+125^{\circ}\text{C}$   |                                                            |                                                                  |
|           | $D_{1a}-D_{1e}$      |       | 350   |               |                                                 |                                                            |                                                                  |
|           | $D_{2a}-D_{2e}$      |       | 350   | $\mu\text{A}$ | $-55^{\circ}\text{C}$                           |                                                            |                                                                  |
| $I_{EE}$  | Power Supply Current | -75   | -25   | mA            | $-55^{\circ}\text{C}$ to $+125^{\circ}\text{C}$ | Inputs Open                                                | (Notes 3, 4, 5)                                                  |
|           |                      |       |       |               |                                                 |                                                            |                                                                  |

**Note 3:** F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals  $-55^{\circ}\text{C}$ ), then testing immediately without allowing for the junction temperature to stabilize due to heat dissipation after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

**Note 4:** Screen tested 100% on each device at  $-55^{\circ}\text{C}$ ,  $+25^{\circ}\text{C}$ , and  $+125^{\circ}\text{C}$ , Subgroups, 1, 2, 3, 7, and 8.

**Note 5:** Sample tested (Method 5005, Table I) on each manufactured lot at  $-55^{\circ}\text{C}$ ,  $+25^{\circ}\text{C}$ , and  $+125^{\circ}\text{C}$ , Subgroups A1, 2, 3, 7, and 8.

**Note 6:** Guaranteed by applying specified input condition and testing  $V_{OH}/V_{OL}$ .

## AC Electrical Characteristics

$V_{EE} = -4.2V$  to  $-5.7V$ ,  $V_{CC} = V_{CCA} = GND$

| Symbol    | Parameter                       | $T_C = -55^\circ C$ |      | $T_C = +25^\circ C$ |      | $T_C = +125^\circ C$ |      | Units | Conditions   | Notes           |
|-----------|---------------------------------|---------------------|------|---------------------|------|----------------------|------|-------|--------------|-----------------|
|           |                                 | Min                 | Max  | Min                 | Max  | Min                  | Max  |       |              |                 |
| $t_{PLH}$ | Propagation Delay               | 0.30                | 1.90 | 0.40                | 1.80 | 0.30                 | 2.30 | ns    | Figures 1, 2 | (Notes 7, 8, 9) |
| $t_{PHL}$ | $D_{na}-D_{ne}$ to O, $\bar{O}$ |                     |      |                     |      |                      |      |       |              |                 |
| $t_{PLH}$ | Propagation Delay               | 0.80                | 2.90 | 0.90                | 2.80 | 0.90                 | 3.40 | ns    |              | (Note 10)       |
| $t_{PHL}$ | Data to F                       |                     |      |                     |      |                      |      |       |              |                 |
| $t_{TLH}$ | Transition Time                 | 0.20                | 1.80 | 0.30                | 1.60 | 0.20                 | 2.00 | ns    |              |                 |
| $t_{THL}$ | 20% to 80%, 80% to 20%          |                     |      |                     |      |                      |      |       |              |                 |

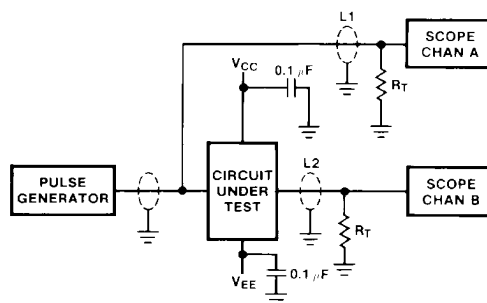
**Note 7:** F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals  $-55^\circ C$ ), then testing immediately after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

**Note 8:** Screen tested 100% on each device at  $+25^\circ C$  temperature only, Subgroup A9.

**Note 9:** Sample tested (Method 5005, Table I) on each mfg. lot at  $+25^\circ C$ , Subgroup A9, and at  $+125^\circ C$  and  $-55^\circ C$  temperatures, Subgroups A10 and A11.

**Note 10:** Not tested at  $+25^\circ C$ ,  $+125^\circ C$ , and  $-55^\circ C$  temperature (design characterization data).

## Test Circuitry



DS100304-5

### Notes:

$V_{CC}$ ,  $V_{CCA} = +2V$ ,  $V_{EE} = -2.5V$

$L1$  and  $L2$  = equal length 50 $\Omega$  impedance lines

$R_T$  = 50 $\Omega$  terminator internal to scope

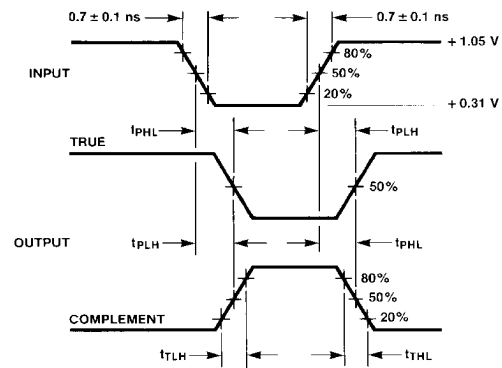
Decoupling 0.1  $\mu F$  from GND to  $V_{CC}$  and  $V_{EE}$

All unused outputs are loaded with 50 $\Omega$  to GND

$C_L$  = Fixture and stray capacitance  $\leq 3$  pF

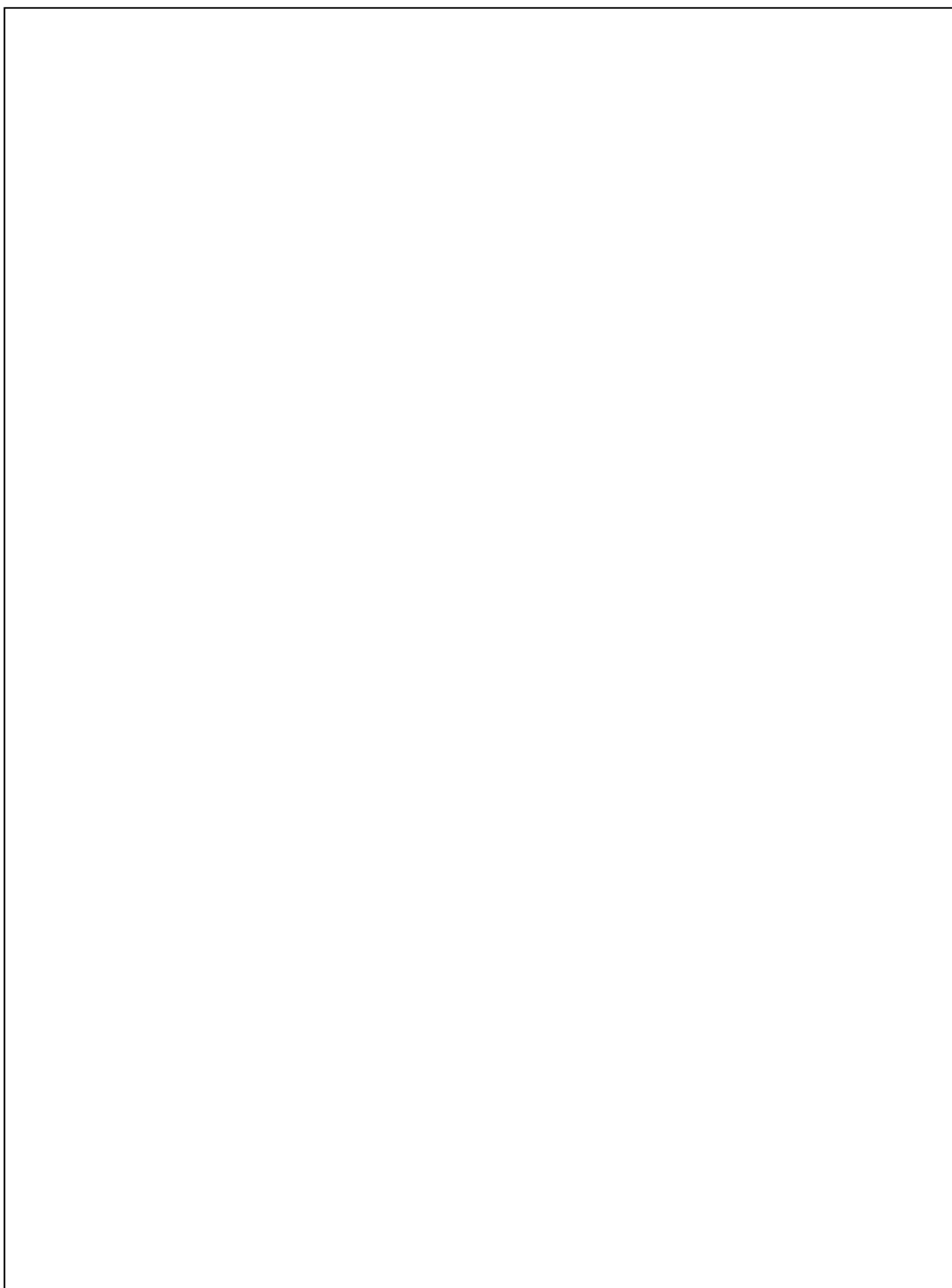
FIGURE 1. AC Test Circuit

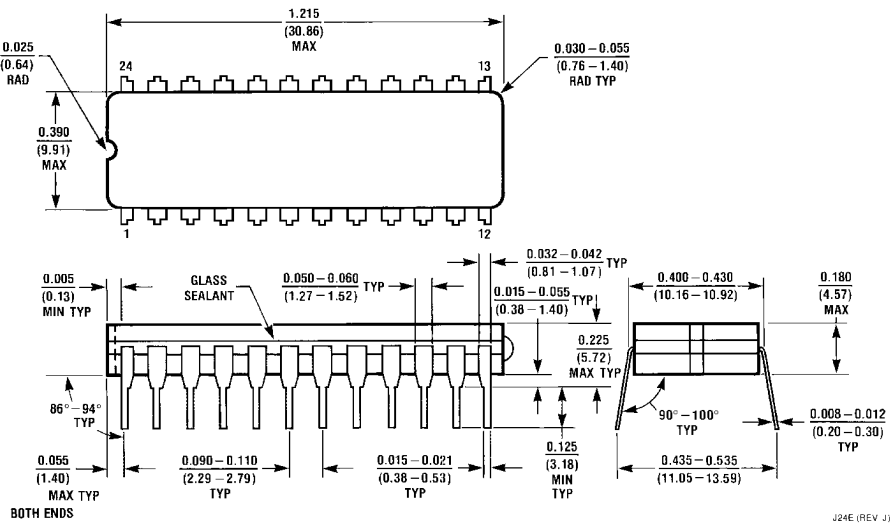
## Switching Waveforms



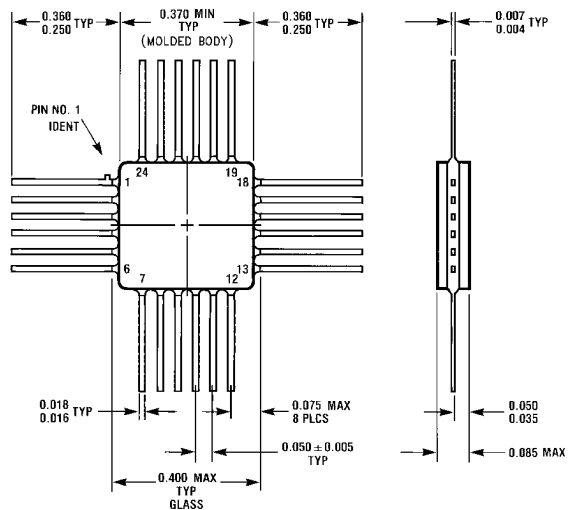
DS100304-6

FIGURE 2. Propagation Delay and Transition Times



**Physical Dimensions** inches (millimeters) unless otherwise noted

**24-Pin Ceramic Dual-In-Line Package (D)**  
**NS Package Number J24E**



24-Pin Quad Cerpak (F)  
NS Package Number W24B